

Search Notes

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VAN T. PHAM

Applicant(s)/Patent under
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YONEZAWA, MINORU

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB) 369 (text search only see search history printout).	7/19/2006	VP